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Application/Contr	ol	No.
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Applicant(s)/Patent under Reexamination

KAGEYAMA ET AL.

09/922,076

Examiner

Art Unit

Minh Dieu Nguyen

2137

	SEARCHED			
Class	Subclass	Date	Examiner	
380	201	12/26/2006	MDN	
705	57, 59	12/26/2006	MDN	
360	60	12/26/2006	MDN	
369	84-85	12/26/2006	MDN	
715	741	12/26/2006	MDN	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
Updated inventor name search on EAST (US-PAT; US-PG-PUB; EPO; JPO; DERWENT, IBM-TDB)	12/26/2006	MDN
Updated text and class search on EAST (US-PAT; US-PG-PUB; EPO; JPO; DERWENT, IBM-TDB)	12/26/2006	MDN
Every claim has been reviewed for 35 USC non-statutory subject matter	12/26/2006	MDN